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|-----------------------------------|--|-------------------------|-----------------------------------------------------------------------|----------------------------------|
| Notice of References Cited | | Application/Control No. | Applicant(s)/Patent Under Reexamination 10/628,546 THIESSEN ET AL. | |
| | | Examiner | Art Unit | Page 1 of 1 MELISSA J. BERMAN |

U.S. PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Name | Classification |
|---|---|--------------------------------------------------|-----------------|-------------------|----------------|
| * | A | US-2003/0023662 A1 | 01-2003 | Yaung, Alan Tsu-I | 709/106 |
| * | B | US-6,532,457 B1 | 03-2003 | Tal et al. | 707/1 |
| * | C | US-2004/0002879 A1 | 01-2004 | Bernhardt et al. | 705/7 |
| | D | US- | | | |
| | E | US- | | | |
| | F | US- | | | |
| | G | US- | | | |
| | H | US- | | | |
| | I | US- | | | |
| | J | US- | | | |
| | K | US- | | | |
| | L | US- | | | |
| | M | US- | | | |

FOREIGN PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Country | Name | Classification |
|---|---|--------------------------------------------------|-----------------|---------|------|----------------|
| | N | | | | | |
| | O | | | | | |
| | P | | | | | |
| | Q | | | | | |
| | R | | | | | |
| | S | | | | | |
| | T | | | | | |

NON-PATENT DOCUMENTS

| | | |
|---|---|------------------------------------------------------------------------------------------------------------------------------------------------------------------------------|
| * | | Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) |
| * | U | Chickering et al. "Efficient Determination of Dynamic Split Points in a Decision Tree", Proceedings of the IEEE International Conference on Data Mining, 29 Nov - 2 Dec 2001 |
| | V | |
| | W | |
| | X | |

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.